

Smart cold electronics

XLZD Meeting 2 Jul 2025

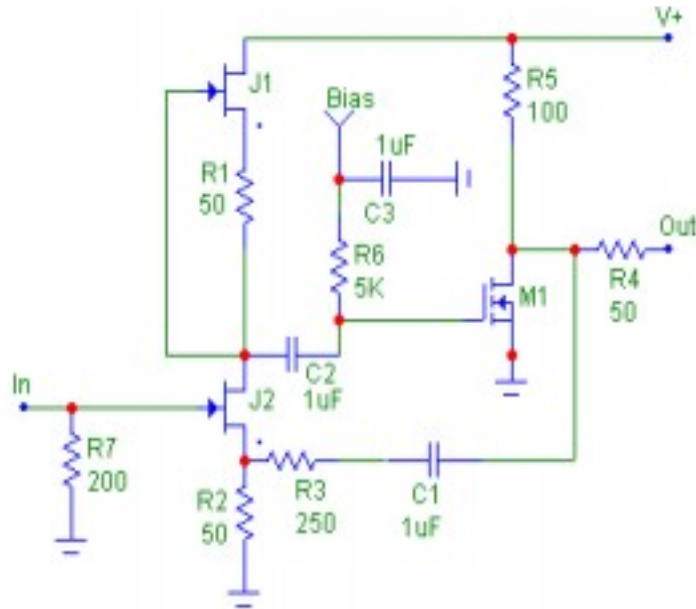
Alessandro Razeto for the LNGS/AQ group

GROUP

- A strong group with proven experience
 - Radiopurity
 - Packaging
 - Photodectors
 - Cryo-electronics
 - Integrated electronics
- LNGS + University of L'Aquila

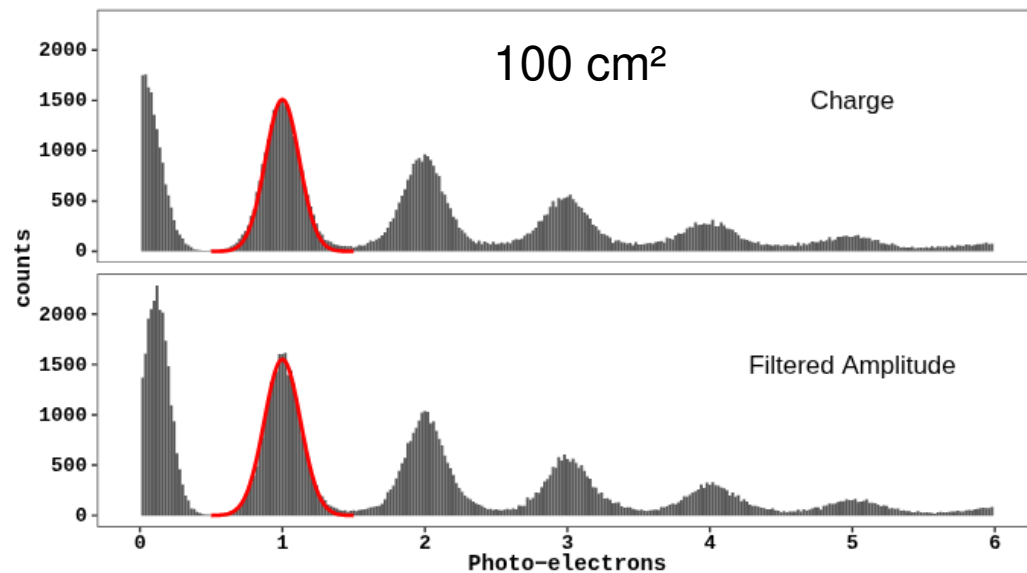
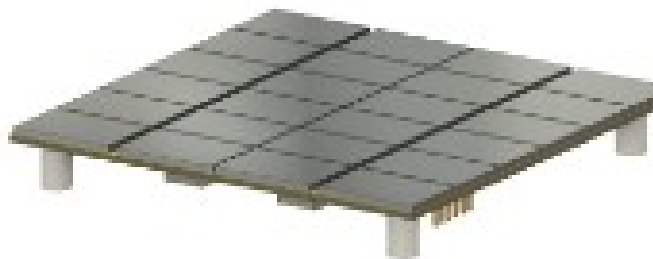
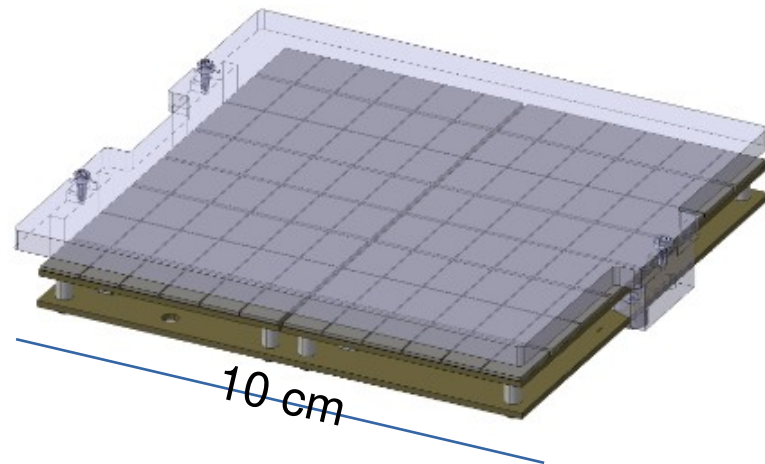
PAST RESULTS

DS-50



PAST RESULTS

DS-20k





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Why cold electronics?

Signal integrity

- A signal to noise over 30 can be easily achieved (see later)
 - A small signal (mV level) on long cable can get noisy and attenuated
 - Pre-amplification produces larger signals that can be easily transmitted for 10 meters with small cables
- The largest noise contribution in XenonNT is from ground loops
 - From single ended (coax) cabling
 - Differential transmission would suppress it
- We could keep PMT HV lower
 - Improve long term stability for PMTs
 - DS50 PMT were running at a gain of 10^5 e⁻ with SNR > 10

Radiopurity

- Coaxial cables are not radiopure
 - Contaminants remain trapped in the mesh
 - Radon emanation
 - Differential transmission over twisted cables with PTFE/FEP jacket
 - With solid conductor – if needed
- Low voltage components are radiopure
 - In term of U/Th
 - Plastic capacitors, inlined resistors, wire bonded chips
 - Largest contamination from the divider components
 - High voltage ceramic capacitors and 10 M Ω resistors
- Radiopure PCBs
 - LNGS will install in the next few years a facility for fused silica PCBs
 - It may be possible to deposit there LV resistors

Integration

- A much simpler detector integration
 - Reduced number of HV cables
 - On divider HV switch
 - Reduced number of signal cabling
 - Easier signal feedtroughs
- Strongly reduce the budget
 - Feedtroughs, digitizers, ... → several M€

Cons

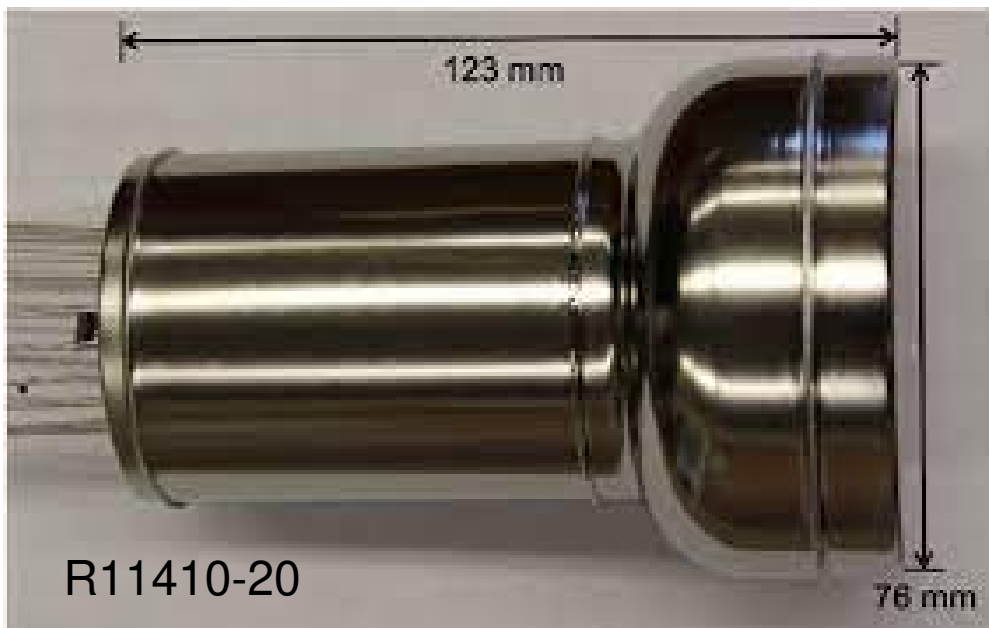
- Of course things can go wrong
 - More components that can fail
- Not everything can be done in cold
 - Full digitization not possible
 - Limited by the power dissipation in LXe
- The dynamic range of each channel will be smaller
 - PMTs can reach 10^5 photons
 - Impossible to match with standard configuration
(but semi-logarithmic solutions can be implemented)
- Immutable
 - Once the detector is installed it is hard to modify the read-out chain



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PMTs

PMTs

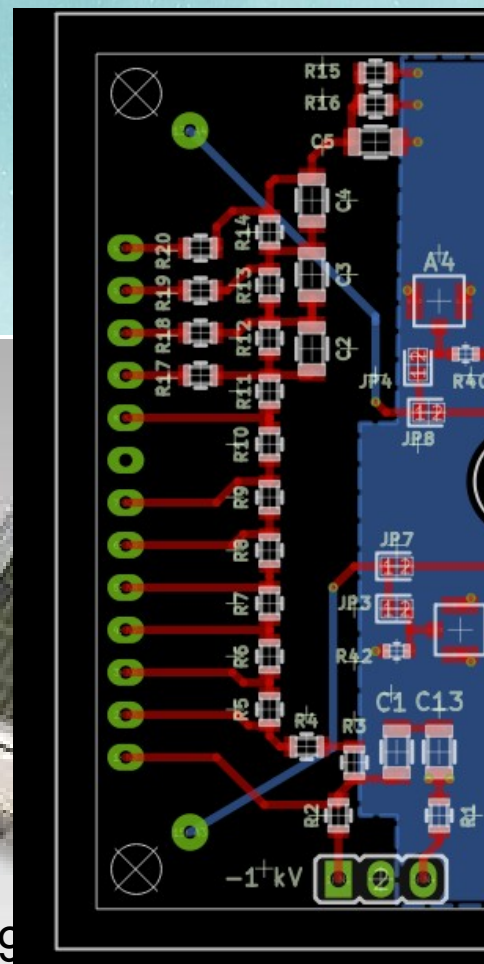


PMTs



R1141020

76 mm



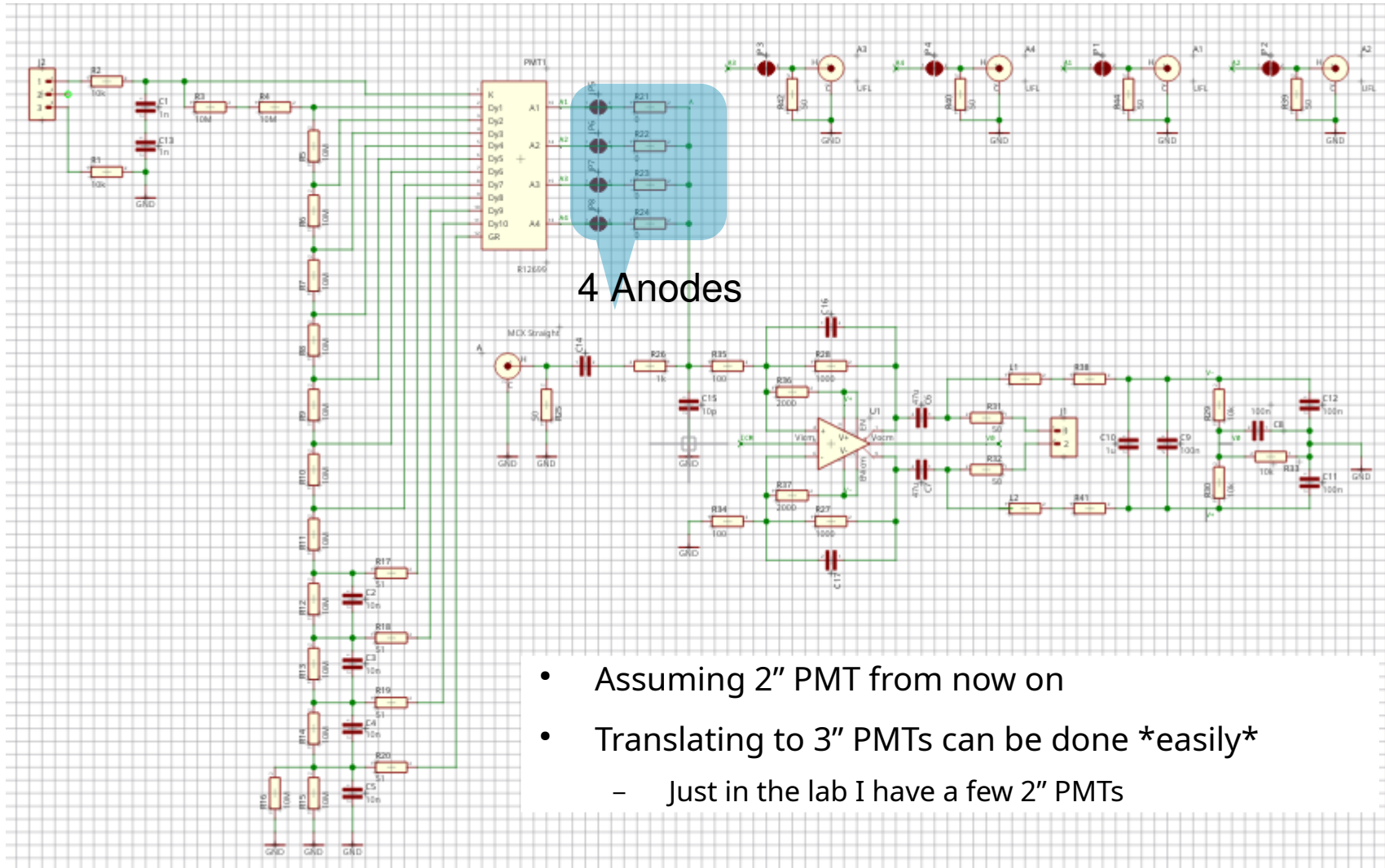
R1269



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A graded approach
Amplify in cold and digitize outside

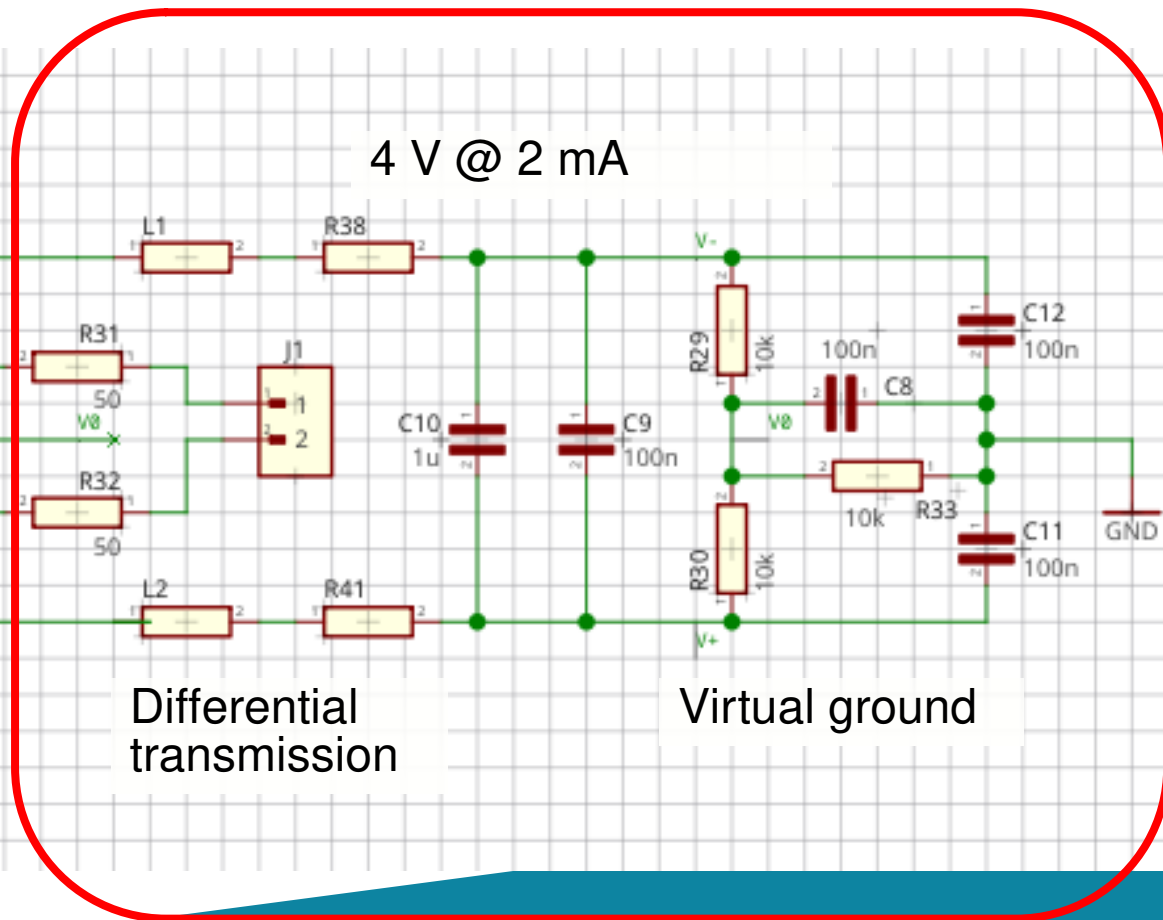
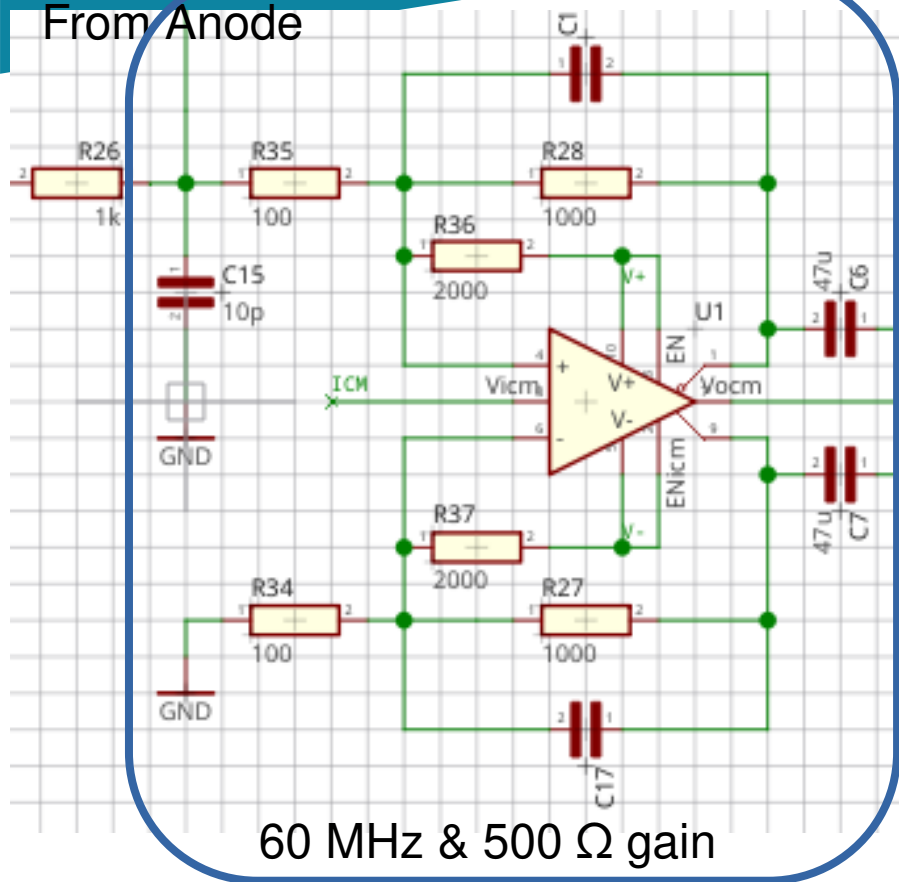
Fully differential TIA



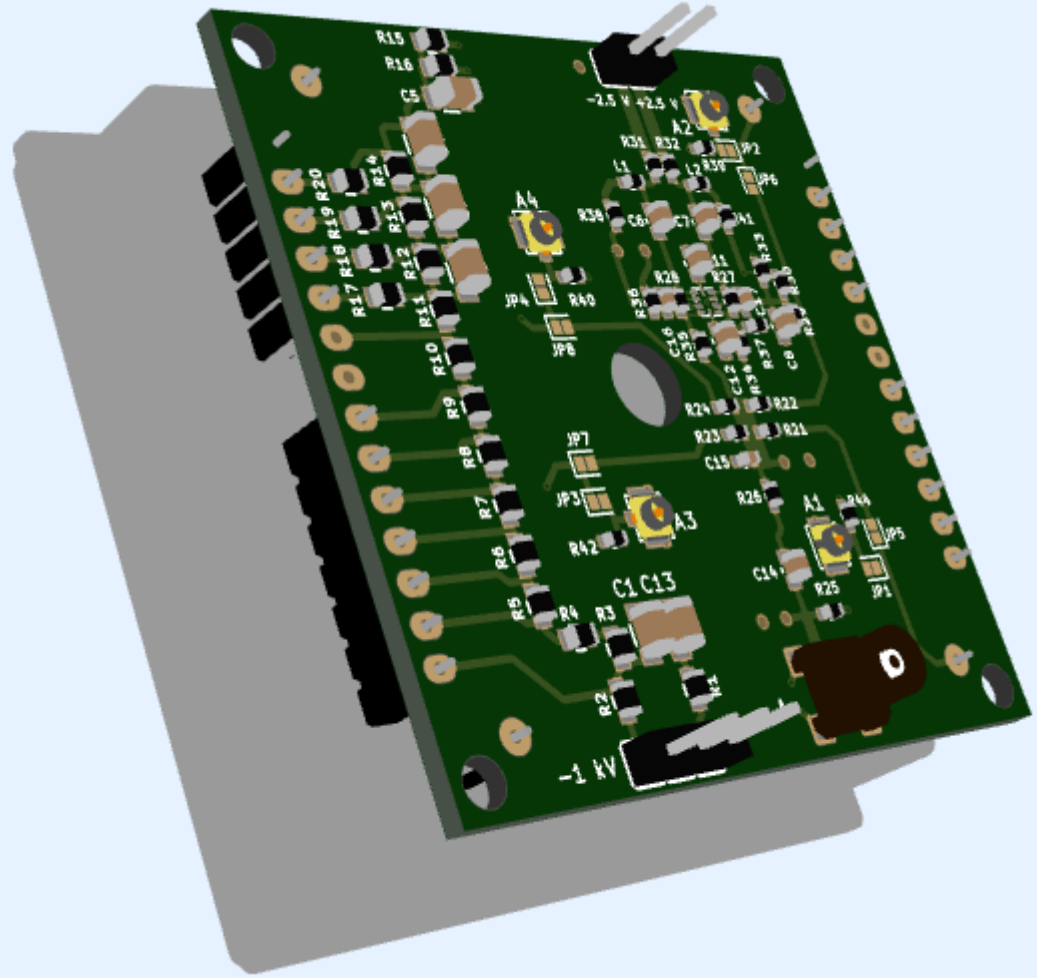
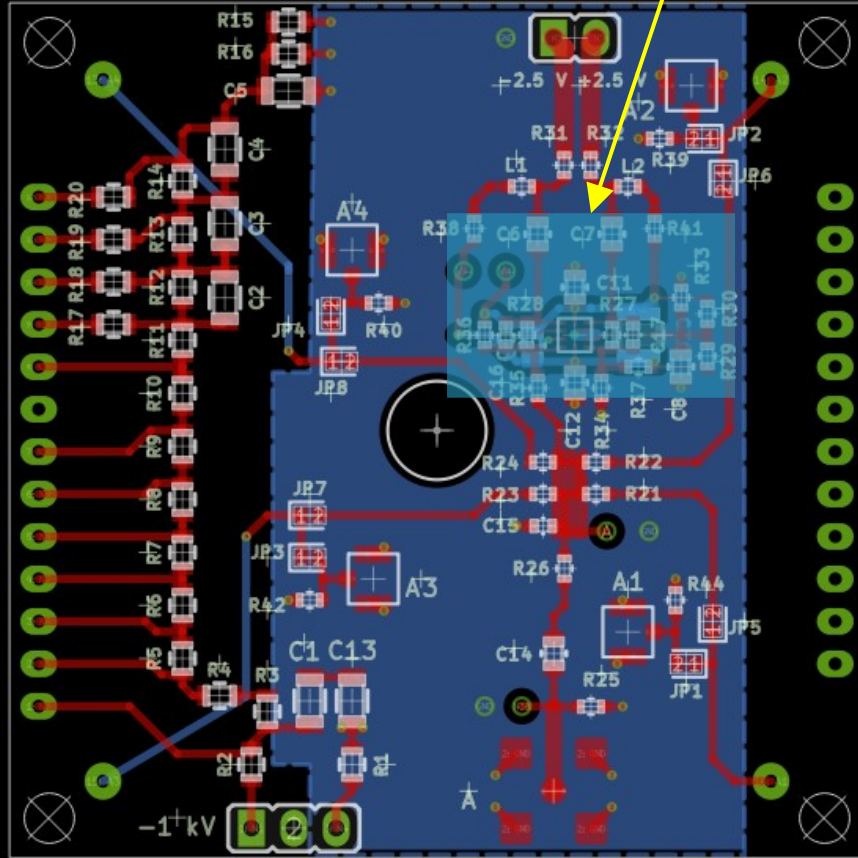
- Assuming 2" PMT from now on
- Translating to 3" PMTs can be done *easily*
 - Just in the lab I have a few 2" PMTs

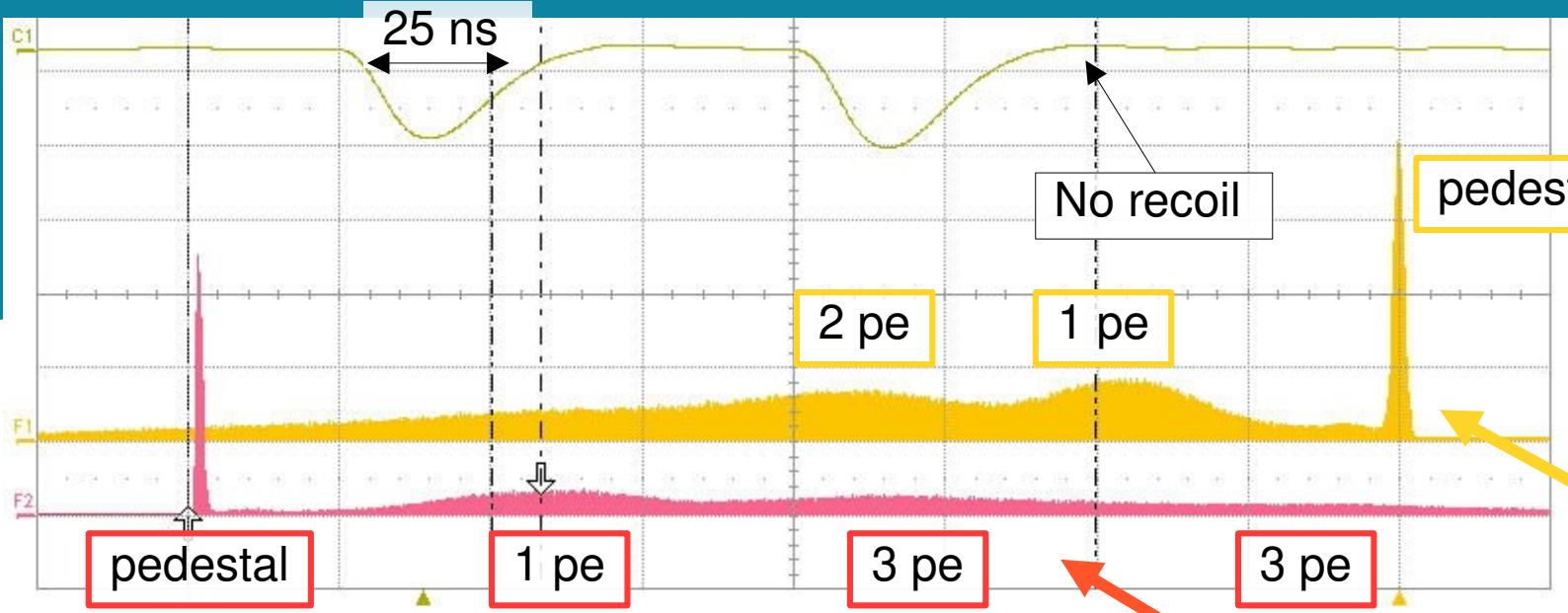
Parasitic power

From Anode



10x15 mm²





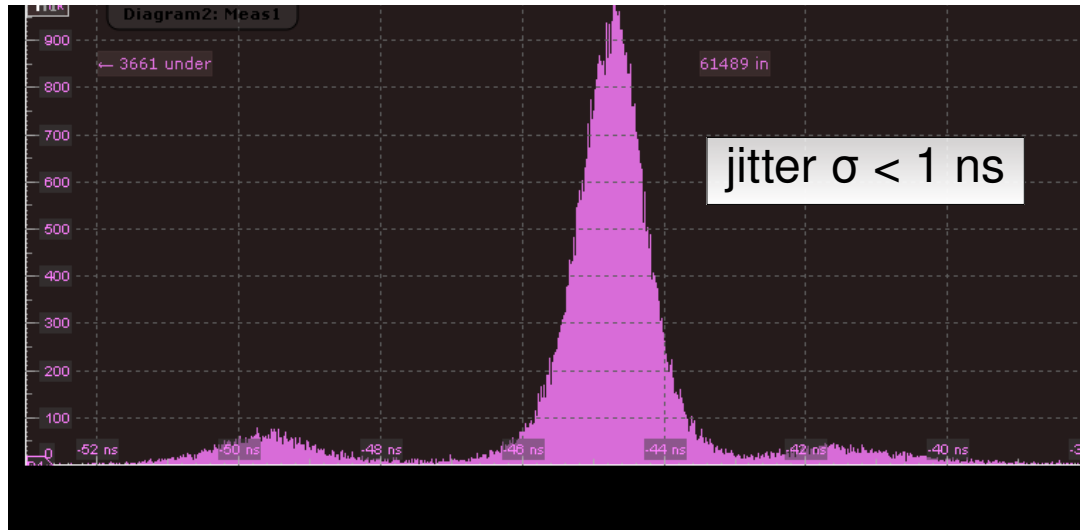
PMT @ 1000 V

Charge

- Gain $2 \cdot 10^6 e^-$
- Noise $3 \cdot 10^4 e^-$
- SNR 75

Amplitude

- Gain 25 mV
- Noise 150 μV
- SNR 150





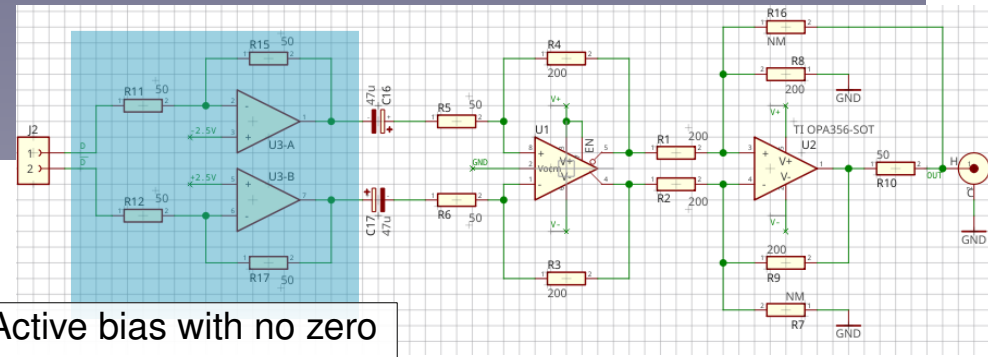
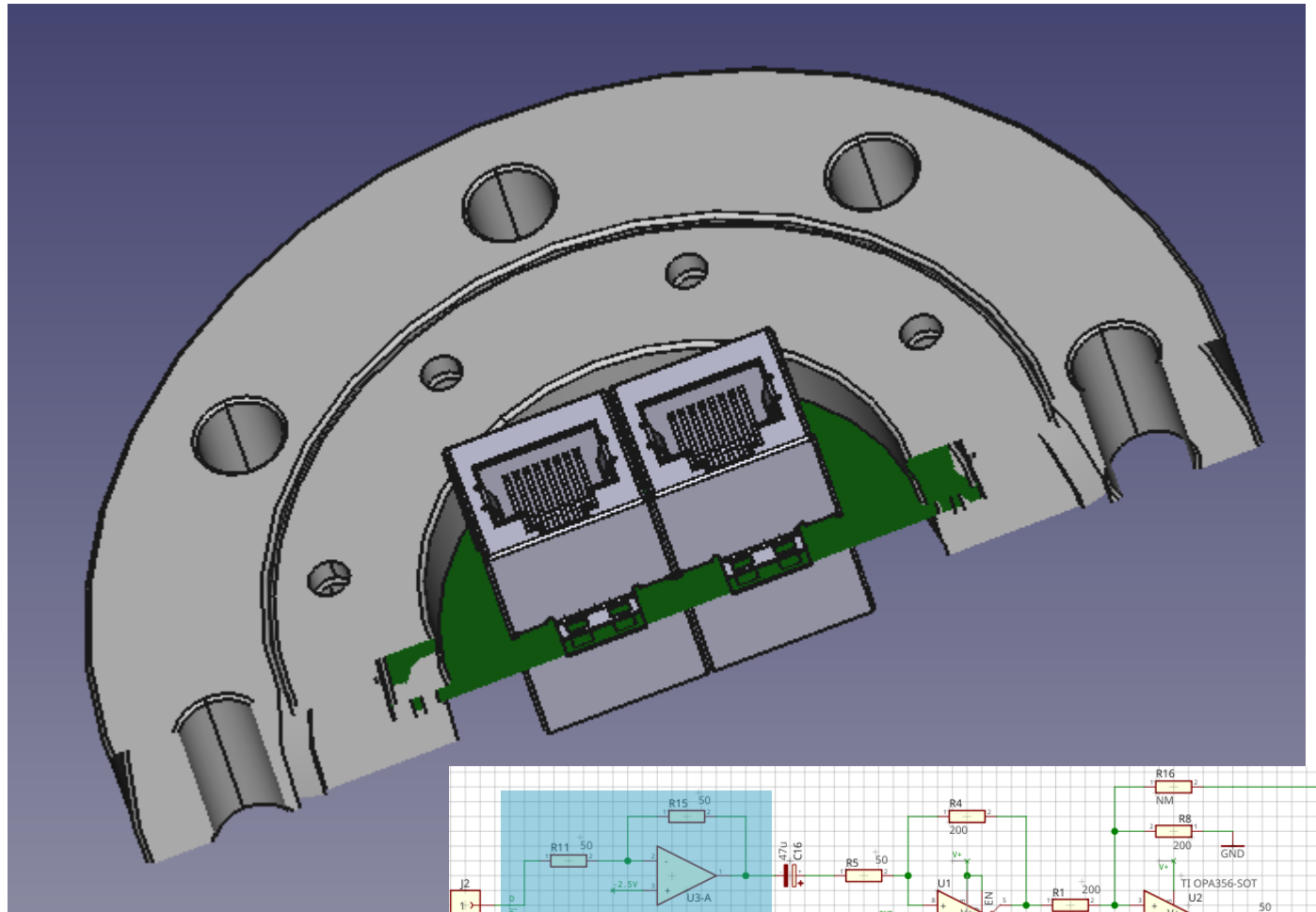
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A graded approach
Cabling

Cabling

- Differential transmission goes with twisted pairs
 - The simplest solution is a pair from a CAT.6 RJ45 cable
 - Yes the ethernet cable
 - PTFE isolated
 - SAMI produced radiopure twisted pair cables for LEGEND
- The feedtroughs can be implemented with PCB
 - Leak < 10^{-10} mbar/l/s
- A differential to single ended receiver can be used

Cabling





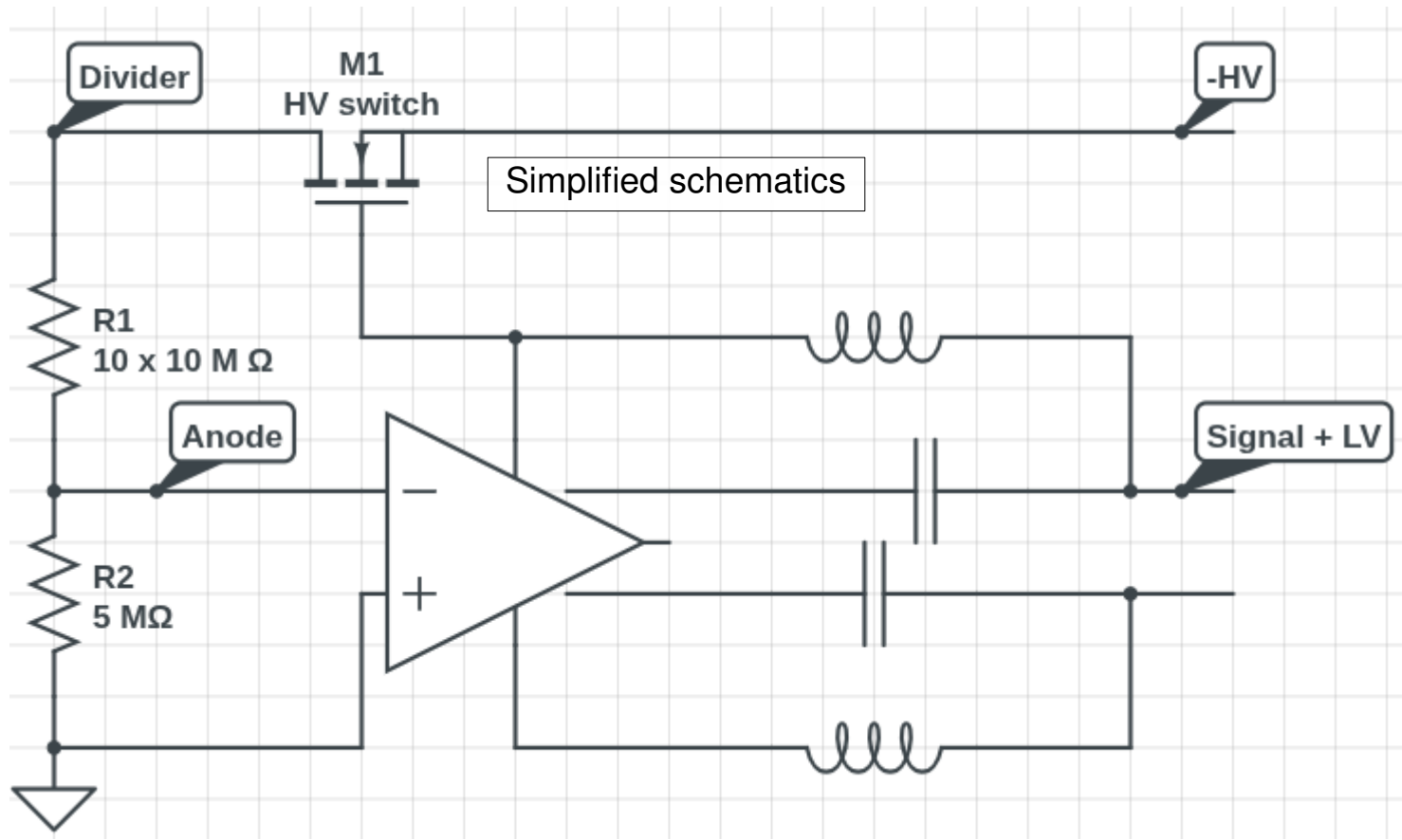
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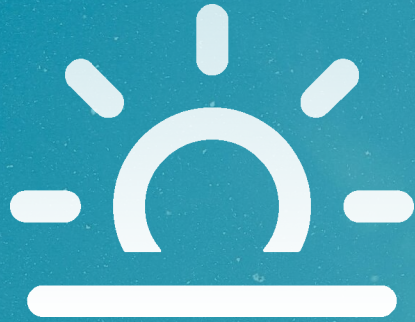
A graded approach
HV distribution

HV distribution

- It is possible to bin the PMTs in groups with similar curve HV-vs-GAIN
 - During the acceptance tests
- We suggest to bring a single HV to group of similar PMTs
 - One each 25?
- Then each PMT can turn off by itself when needed
 - With an on-board switch
 - Without additional cables or controls
 - Remove power to the cold-amplifier and disable the PMT as well

HV distribution





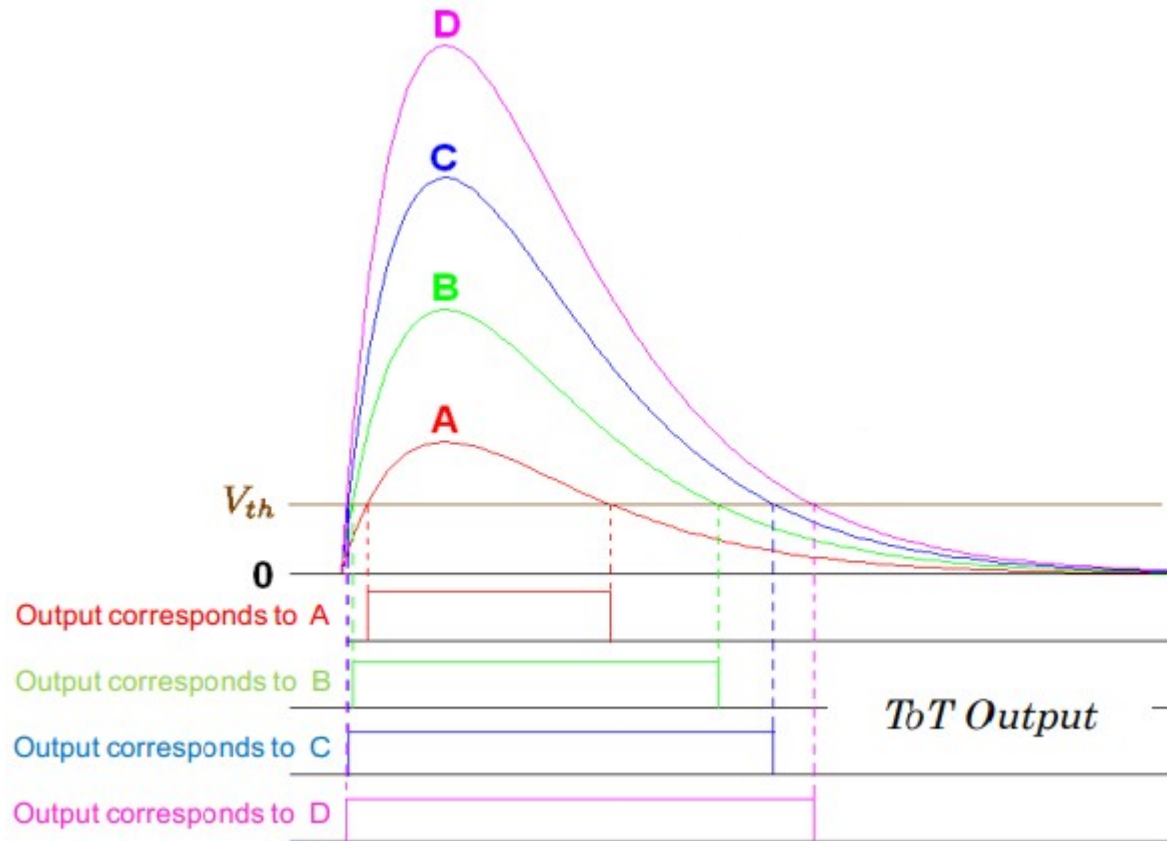
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A graded approach
Amplify and digitize cold

Digitize at cold

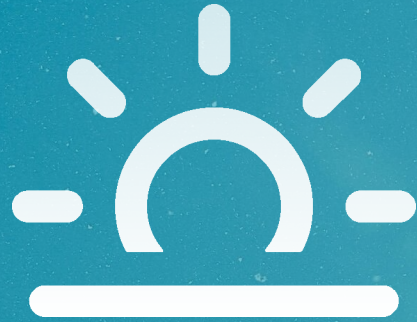
- We have the technology to develop chips working in LXe
 - PDK certified in cryogenic environment
- A full digitizer however uses way too much power
 - Too much heat would prevent Rn-chain topological tagging
 - Boubbling
- The proposed solution is to develop a programmable TDC with time over threshold
 - Per each anode - $2.5 \times 2.5 \text{ cm}^2$
 - And to bring out the sum of a PMT group analog signal

Time over Threshold



Time & amplitude for each photoelectron

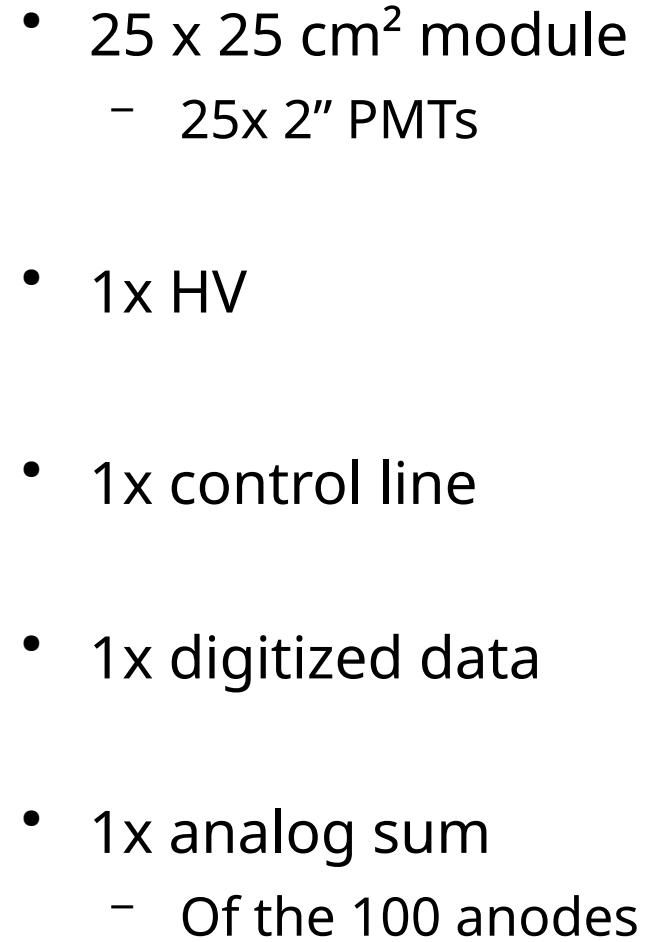
~ 10k anode in XLZD, the pileup of S1 at 3 MeV ~ 3 pe per channel



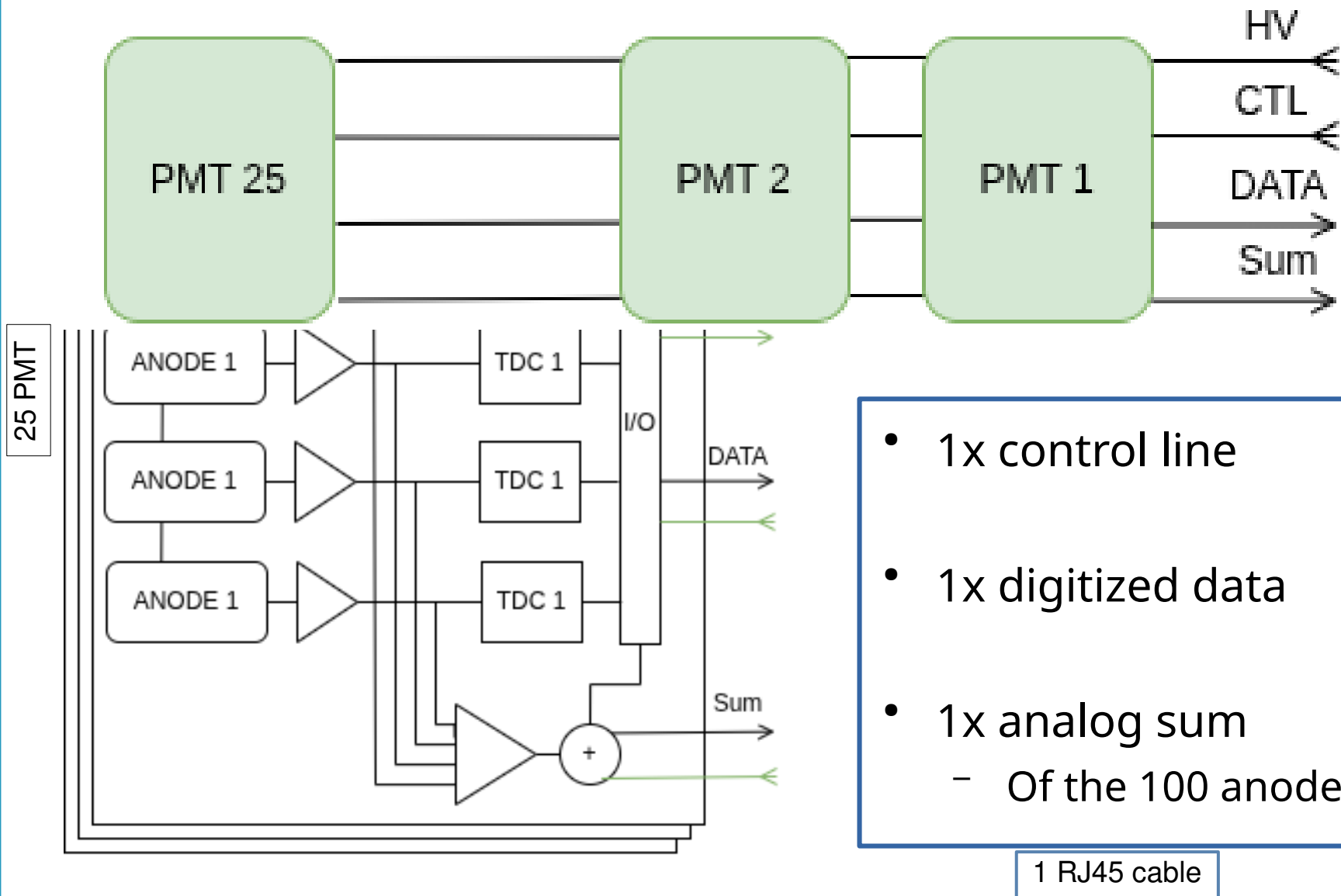
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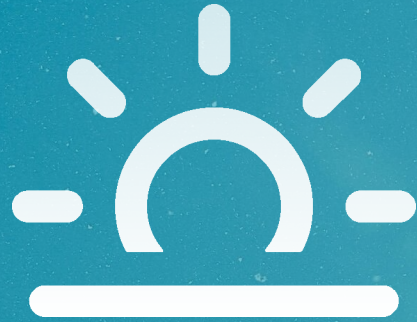
A graded approach
Fully integrated solution

25 PMT



Integrated unit





Summary

- We already have a cryogenic pre-amplifier
 - Low noise
 - Low power
 - Low radioactive ← will require some time depending on the PCB choice
- A highly integrated unit can be developed in a few years
 - 25x25 cm² aggregated photodetector with 2" PMTs
 - with a single HV and a single RJ cable for signal and control
 - With low power (20 mW/PMT) and high radiopure components
 - 3" PMTs can be used as well → 4x4 PMTs
 - Maybe with a PCB piggyback for the cold-electronics
- The LNGS group is actively working on this topic
 - Proven results with simple pre-amplifier
 - Working on the ASIC design
 - Working on the smart power distribution
 - Working on radiopure PCBs

Thank you

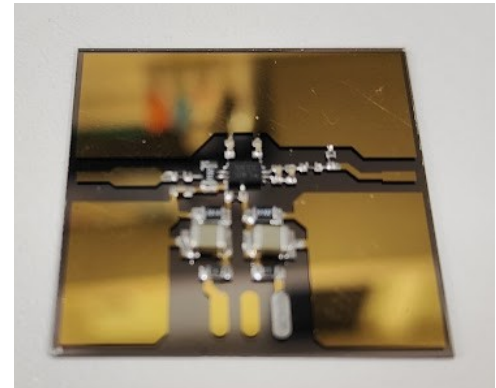


Technologies

To overcome the limitations

Radio-purity

- Ceramic capacitors have high U & Th
 - Plastic, silicon, tantalum capacitors have low high-Z contaminations
 - Though they may have 40K and other traces
- PCB can be produced in fused silica
 - With embedded resistors with laser trimming
 - Or in pyralux/cyrlex/...
- Connectors contain glass-fiber
 - can be produced out of pure nylon
- Radio-pure inductors exists



Technologies

- Pure Si BJT not working below 200 K
 - Freeze-out of minority carriers
 - Ethero-junction BJT are working down to 20 K
 - With very low noise figure
- FET transistors are working in LN2
 - Based on majority carriers
- For both technologies both single transistors and op-amp are available

Field effect transistors

Field effect transistors are based on majority carriers

- FETs work down to the freeze-out
- Higher gain and bandwidth
- Lower noise
- LOW POWER

Problems:

- JFETs have increased noise below 120 K
- Hot carriers reduce life of devices
- Increased 1/F noise
- Trapping / Recombination

Rescia @ Mi
Radeka @ BNL

